

MOS FIELD EFFECT TRANSISTOR **2SK3060**

SWITCHING N-CHANNEL POWER MOS FET INDUSTRIAL USE

DESCRIPTION

The 2SK3060 is N-Channel MOS Field Effect Transistor designed for high current switching applications.

FEATURES

· Low on-state resistance

 $R_{DS(on)1} = 13 \text{ m}\Omega \text{ MAX. (VGs} = 10 \text{ V, ID} = 35 \text{ A)}$

 $R_{DS(on)2} = 20 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = 4.0 \text{ V, ID} = 35 \text{ A)}$

- Low Ciss: Ciss = 2400 pF TYP.
- Built-in gate protection diode

ORDERING INFORMATION

PART NUMBER	PACKAGE
2SK3060	TO-220AB
2SK3060-S	TO-262
2SK3060-ZJ	TO-263
2SK3060-Z	TO-220SMD ^{Note}

Note This package is produced only in Japan.

ABSOLUTE MAXIMUM RATINGS (TA = 25 °C)

Drain to Source Voltage (Vgs = 0 V)	VDSS	60	V
Gate to Source Voltage (Vps = 0 V)	Vgss(ac)	±20	V
Gate to Source Voltage (Vps = 0 V)	VGSS(DC)	+20, -10	V
Drain Current (DC)	I _{D(DC)}	±70	Α
Drain Current (Pulse) Note1	D(pulse)	±210	Α
Total Power Dissipation (Tc = 25°C)	PT	70	W
Total Power Dissipation (T _A = 25°C)	Рт	1.5	W
Channel Temperature	Tch	150	°C
Storage Temperature	Tstg	-55 to +150	°C
Single Avalanche Current Note2	las	35	Α
Single Avalanche Energy Note2	Eas	122.5	mJ

Notes 1. PW \leq 10 μ s, Duty cycle \leq 1%

2. Starting T_{ch} = 25°C, R_G = 25 Ω , V_{GS} = 20 V \rightarrow 0 V

(TO-220AB)



(TO-262)



(TO-263, TO-220SMD)

THERMAL RESISTANCE

 $\begin{array}{cccc} \text{Channel to Case} & & \text{R}_{\text{th(ch-C)}} & & 1.79 & \text{°C/W} \\ \text{Channel to Ambient} & & \text{R}_{\text{th(ch-A)}} & & 83.3 & \text{°C/W} \\ \end{array}$



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Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.

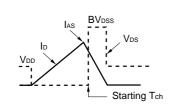


ELECTRICAL CHARACTERISTICS (TA = 25°C)

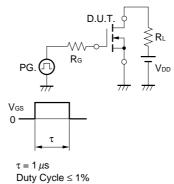
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain to Source On-state Resistance	RDS(on)1	V _G S = 10 V, I _D = 35 A		11	13	mΩ
	RDS(on)2	Vgs = 4.0 V, ID = 35 A		16	20	mΩ
Gate to Source Cut-off Voltage	V _{GS(off)}	V _{DS} = 10 V, I _D = 1 mA	1.0	1.5	2.0	V
Forward Transfer Admittance	y _{fs}	V _{DS} = 10 V, I _D = 35 A	15	50		S
Drain Leakage Current	IDSS	Vps = 60 V, Vgs = 0 V			10	μΑ
Gate to Source Leakage Current	Igss	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μΑ
Input Capacitance	Ciss	Vps = 10 V		2400		pF
Output Capacitance	Coss	Vgs = 0 V		700		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		280		pF
Turn-on Delay Time	td(on)	ID = 35 A		30		ns
Rise Time	tr	V _{GS(on)} = 10 V		600		ns
Turn-off Delay Time	td(off)	$V_{DD} = 30 \text{ V}$		140		ns
Fall Time	t _f	$R_G = 10 \Omega$		450		ns
Total Gate Charge	QG	ID = 70 A		50		nC
Gate to Source Charge	Qgs	VDD = 48 V		7.5		nC
Gate to Drain Charge	Q _{GD}	Vgs = 10 V		18		nC
Body Diode Forward Voltage	V _F (S-D)	IF = 70 A, Vgs = 0 V		1.0		V
Reverse Recovery Time	trr	IF = 70 A, VGS = 0 V		55		ns
Reverse Recovery Charge	Qrr	$di/dt = 100 A/\mu s$		75		nC

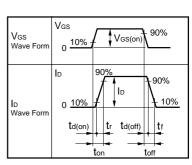
TEST CIRCUIT 1 AVALANCHE CAPABILITY

$\begin{array}{c|c} \text{D.U.T.} \\ \text{RG} = 25 \ \Omega \\ \text{PG.} \\ \hline \\ \text{VGS} = 20 \rightarrow 0 \ V \\ \end{array} \begin{array}{c} \text{D.U.T.} \\ \\ \text{PG.} \\ \hline \\ \end{array} \begin{array}{c} \text{VDD} \\ \\ \end{array}$

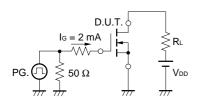


TEST CIRCUIT 2 SWITCHING TIME

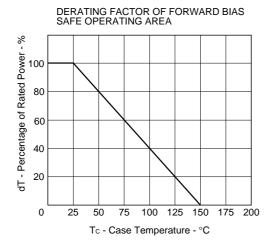


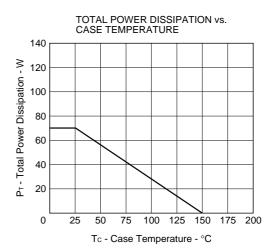


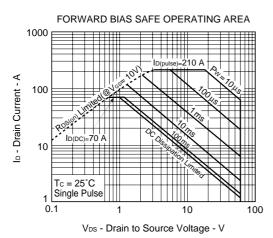
TEST CIRCUIT 3 GATE CHARGE



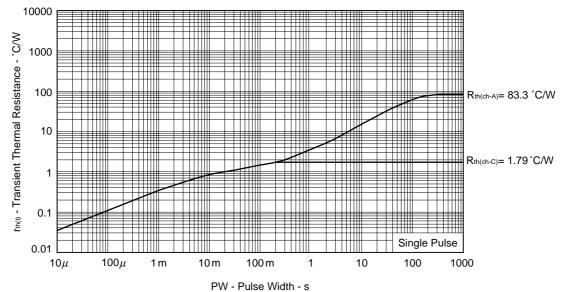
TYPICAL CHARACTERISTICS (TA = 25°C)



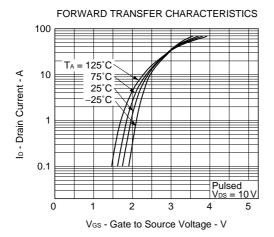


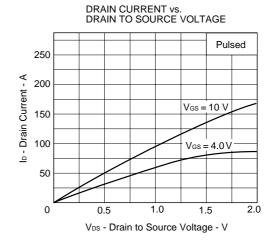


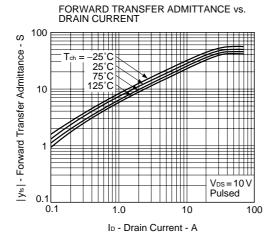
TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

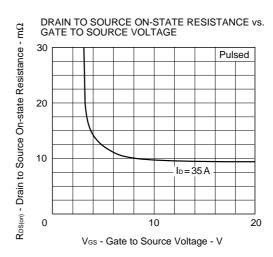


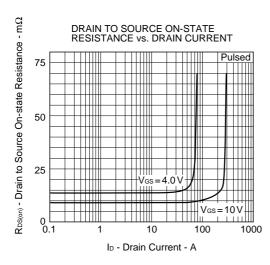
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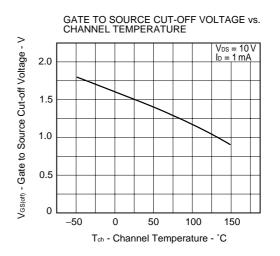


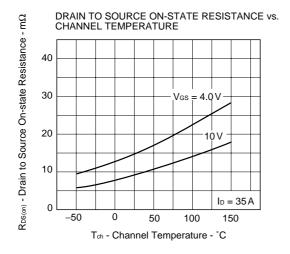


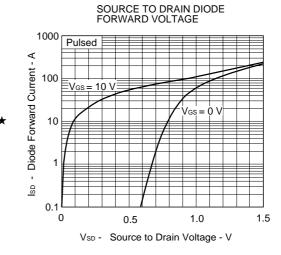


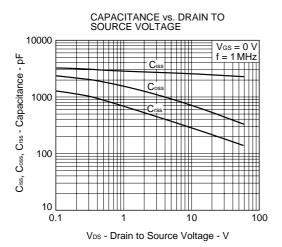


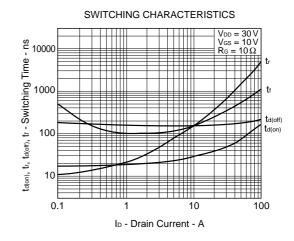


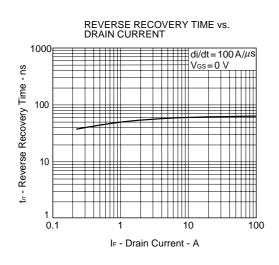


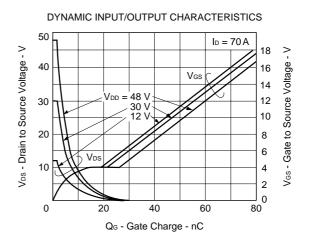


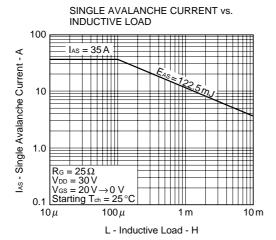


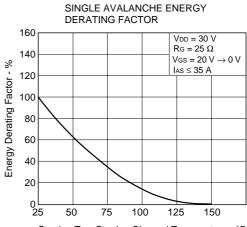










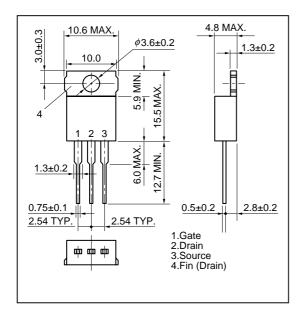


Starting T $_{\text{ch}}$ - Starting Channel Temperature - $^{\circ}\text{C}$

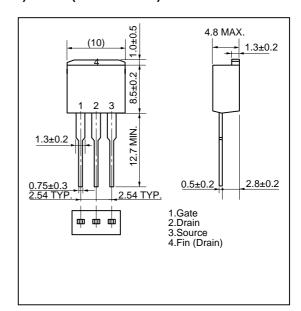


PACKAGE DRAWINGS (Unit:mm)

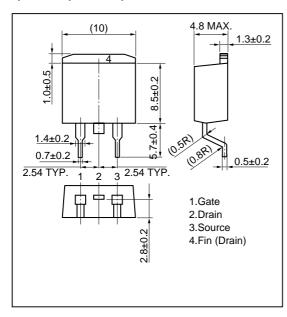
1)TO-220AB (MP-25)



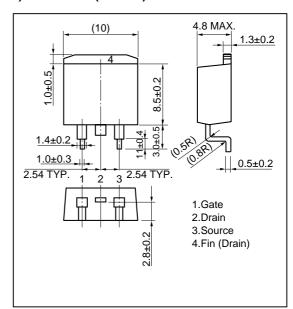
2)TO-262 (MP-25 Fin Cut)



3)TO-263 (MP-25ZJ)

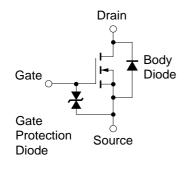


★ 4)TO-220SMD (MP-25Z) Note



Note This package is produced only in Japan.

EQUIVALENT CIRCUIT



Remark

The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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